**Product data sheet** 

# 1. General description

Planar passivated four quadrant triac in a IITO3P package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)}$  = 150 °C). It is used in applications where "high junction operating temperature capability" is required.

### 2. Features and benefits

- · High current TRIAC
- Low thermal resistance
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Insulated tab rated at 2500 V rms

## 3. Applications

- High current / high surge applications
- · High power / industrial controls -- e.g. heating, motors, lighting

#### 4. Quick reference data

#### Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit		
Absolute maximum rating						
$V_{DRM}$	repetitive peak off-state voltage		800	V		
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>mb</sub> ≤ 96 °C; Fig. 1; Fig. 2; Fig. 3	45	A		
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p = 20 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$ ; Fig. 4; Fig. 5	450	А		
		full sine wave; $t_p$ = 16.7 ms; $T_{j(init)}$ = 25 °C	495	Α		
T <sub>j</sub>	junction temperature		150	°C		

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics		,			
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G + T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G+} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	70	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V <sub>T</sub>	on-state voltage	I <sub>τ</sub> = 63.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
Dynamic	characteristics				1	
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	750	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
dI <sub>com</sub> /dt rate of change of commutating current		$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; gate open circuit}$	10	-	-	A/ms

# 5. Pinning information

Table 2. Pinning information

TODIO ZITI	mining imor	- Indiana		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		NI
2	T2	main terminal 2		T2—T1
3	G	gate		sym051
mb	n.c.	mounting base; isolated	IITO3P (SOT1292)	

# 6. Ordering information

**Table 3. Ordering information** 

rabio o. Oraoring iiii	ommunom					
Type number	Package	Orderable part number	Packing	Small packing	Package	Package
	name		method	quantity	version	issue date
BTA45-800B	IITO3P	BTA45-800BQ	Tube	30	SOT1292	21-Jul-2017

# 7. Marking

**Table 4. Marking codes** 

Type number	Marking codes
BTA45-800B	BTA45-800B

# 8. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; $T_{mb} \le 96^{\circ}C$ ; Fig. 1; Fig. 2; Fig. 3	45	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	450	А
		full sine wave; $t_p = 16.7 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$ ;	495	Α
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10ms; sine wave	1012.5	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 150mA	150	A/µs
I <sub>GM</sub>	peak gate current	t <sub>p</sub> = 20µs	8	А
P <sub>GM</sub>	peak gate power	t <sub>p</sub> = 20µs	40	W
$P_{G(AV)}$	average gate power	over any 20 ms period	1	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

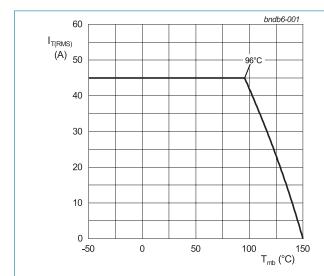
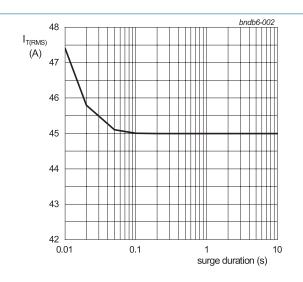
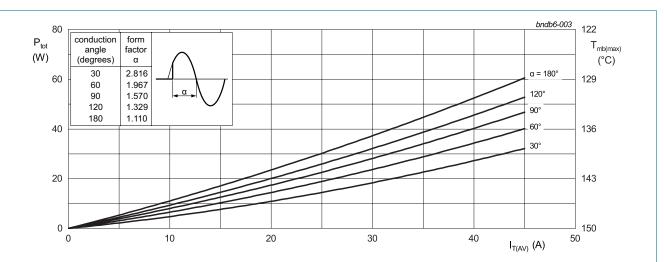


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50Hz; T_{mb} = 96 °C$ 

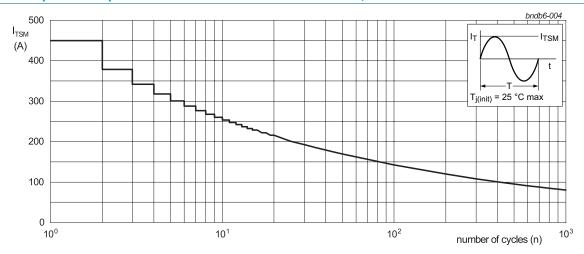
Fig. 2. RMS on-state current as a function of surge duration; maximum values



 $\alpha$  = conduction angle

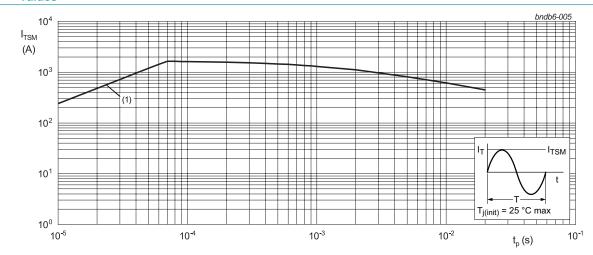
 $a = form factor = I_{T(RMS)} / I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_p \le 20 \text{ ms}$ ; (1)  $dI_T/dt \text{ limit}$ 

Fig. 5. Total power dissipation as a function of RMS on-state current; maximum values

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### 9. Thermal characteristics

**Table 5. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 6	-	-	0.9	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	50	-	K/W

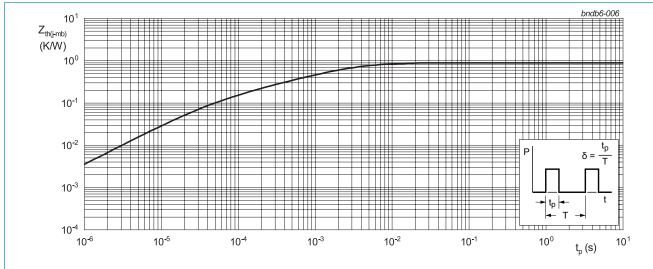


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

### 10. Isolation characteristics

**Table 6. Isolation characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{isol(RMS)}$	RMS isolation voltage	from all terminal to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz $\leq$ f $\leq$ 60 Hz; RH $\leq$ 65 %; $T_h = 25$ °C	-	-	2500	V

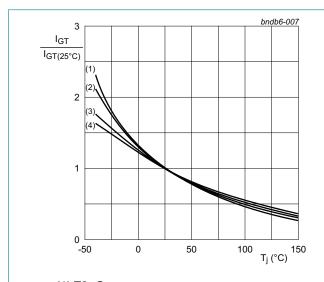
## 11. Characteristics

Table 7 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics	·				
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;}$ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G+;}$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	70	mA
IL	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	100	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	160	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	100	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	100	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V <sub>T</sub>	on-state voltage	I <sub>τ</sub> = 63.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
V <sub>GT</sub> gate trigger voltage		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.8	1.3	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C};$ Fig. 11	0.2	0.45	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	2.5	mA
Dynamic o	characteristics					
dV <sub>D</sub> /dt rate of rise of off-state voltage		of rise of off-state $V_{DM}$ = 536 V; $T_j$ = 125 °C; $(V_{DM}$ = 67%		-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 20\text{A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; \text{ gate open circuit}$	10	-	-	A/ms

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- (1) T2- G+
- (2) T2- G-
- (3) T2+ G-
- (4) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

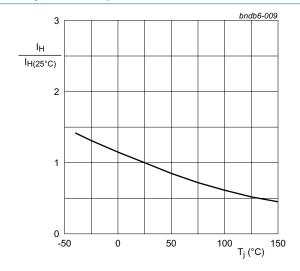


Fig. 9. Normalized holding current as a function of junction temperature

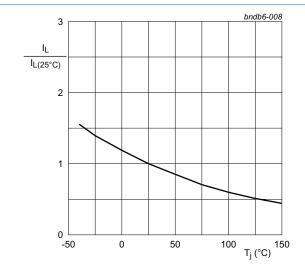
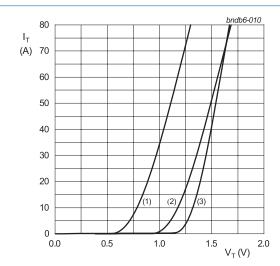


Fig. 8. Normalized latching current as a function of junction temperature

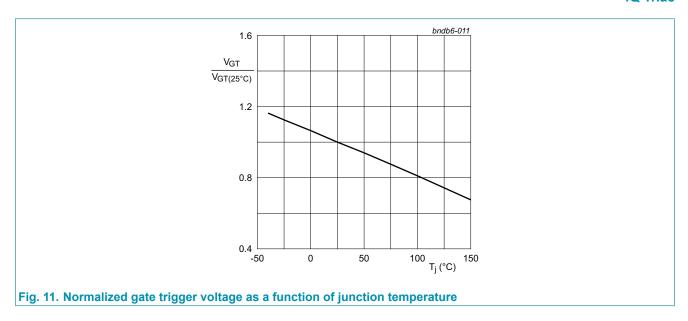


- $V_o$  = 1.155 V;  $R_s$  = 0.0068  $\Omega$
- (1) T<sub>j</sub> = 150 °C; typical values (2) T<sub>j</sub> = 150 °C; maximum values
- (3)  $T_i = 25$  °C; maximum values

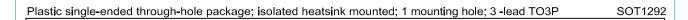
Fig. 10. On-state current as a function of on-state voltage

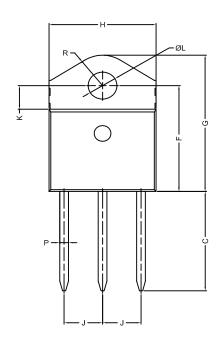
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# 12. Package outline







	Unit		А	В	С	D	E	F	G	Н	_	К	L	Р	R
Ī	мм	min	4.75	1.45	14.35	0.50	2.70	15.80	20.40	15.10	5.40	3.40	4.08	1.20	4.6
L	1111	max	4.95	1.55	15.60	0.70	2.90	16.50	21.10	15.50	5.65	3.65	4.17	1.40	(typ.)

VERSION IEC JEDEC EIAJ PROJECTION	OUTLINE		REFEREN	EUROPEAN	ISSUE DATE	
SOT1292	VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
	SOT1292		-		$\bigoplus_{\bigoplus}$	

### 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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